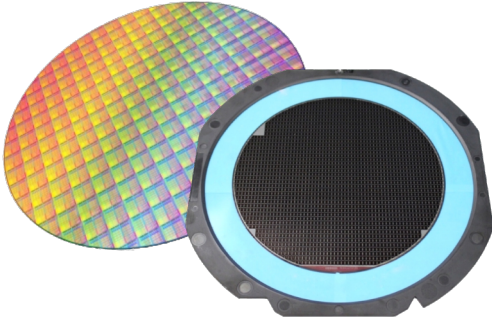


# Wafer Surface Inspection

Wafers are used in both commercial and military applications for all types of microelectronics and optical applications.

MVP with their latest technologies, can accurately and efficiently inspect surface defects such as Surface defects, FM, scratches, contamination, edge cracks, die surfaces and dimensions.



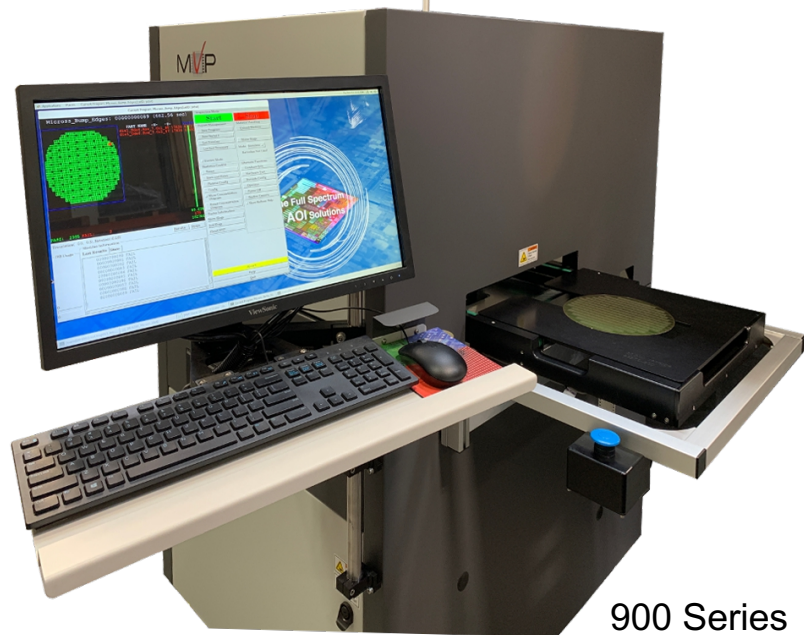
## Solutions for Wafer or Film Frames

MVP's systems have the ability to inspect wafers in low volume environments using a carrier load or in high volume environments with automated loading from standard magazines.

Our standard systems support:

**Wafers:** 100mm, 150mm, 200mm & 300mm.

**Film Frames:** Up-to 15"

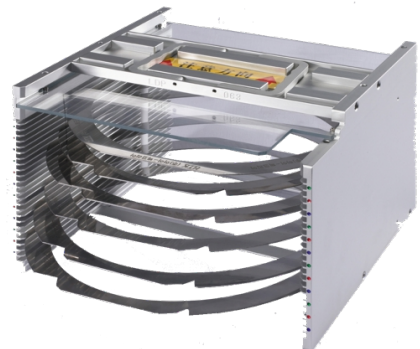


900 Series

Automated Load From Carrier or Robotic Arm



Magazine Loading for Film-Frames



MVP's AutoData tools can provide full traceability. Options also allow for Image archiving and full variable data retention. For more information, please contact MVP.